Supplementary Information:

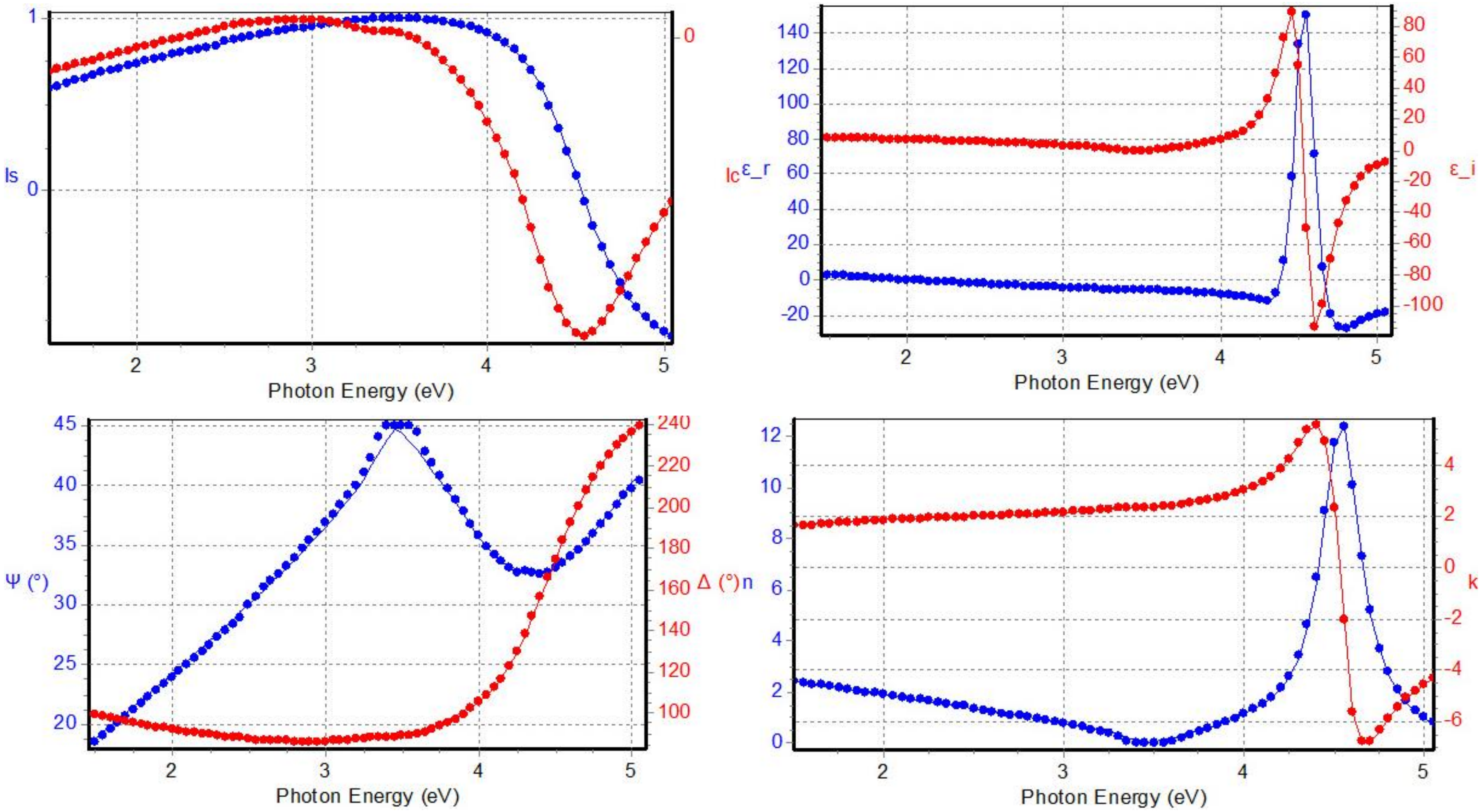

Fig. S1. Comparison between acquired ellipsomtery data (data points) and the classical dispersion model fit (solid line) used for oxide layer thickness measurements (for case 900^0 C).